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LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT		Applicant: Klaus Dworski et al.
Filing Date: January 13, 2006		Group Art: Unknown

## U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Name	Class	Sub Class	Filing Date If Appropriate
/MN/	AA	2002/0105353	08/2002	Mori et al.		
	AB	3,852,123	12/1974	Goltz		
	AC	4,746,902	05/1988	Tol et al.		
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## FOREIGN PATENT DOCUMENTS

	Document No.	Date	Country	Class	Sub Class	Translated Yes No
/MN/	AM	0 550 187	07/1993	EPO		Yes
	AN					Yes
	AO					Yes

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

/MN/	AP	A.K. Lu, G.W. Roberts, "An Analog Multi-Tone Signal Generator for Built-In Self-Test Applications", ITC 1994 Proceedings, Baltimore, USA Paper 27.3, pp. 650-659.
	AQ	A.K. Lu, G.W. Roberts, D.A. Johns, "A High-Quality Analog Oscillator Using Oversampling D/A Conversion Techniques", ISCAS 1993 Proceedings, Chicago, May 1993, pp. 1298-1301.
	AR	A.K. Lu, G.W. Roberts, D.A. Johns, "A High-Quality Analog Oscillator Using Oversampling D/A Conversion Techniques", IEEE Trans. On Circuits and Systems - II: Analog and Digital Signal Processing, Vol. 41, No. 7, July 1994.
	AS	M. Hafed, G. Roberts, "Test and Evaluation of Multiple Embedded Mixed-Signal Test Cores", ITC 2002 Proceedings, Baltimore, USA, Paper 35.3, pp. 1022-1030.
	AT	T.A. Rebold, F.H. Irons: "A phase-plane approach to the compensation of high-speed analog-to-digital converters" IEEE International Symposium on Circuits and Systems XP 008036387 . 1987.
/MN/	AU	Hofner T.C.: "INL/DNL Measurements for High-Speed ADCS" XP000947286 . 12-1999.

EXAMINER: /Michael Nghiem/

DATE CONSIDERED: 05/20/2009

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.